

RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS2502	Dec-95	9546 A6	CARSEM	DM534661ANA	1.2μ OX/NI EPROM	08 SOIC 150

STRESS/JOB NO.

**READPOINT
(Sample Size/No. of Fails)**

Preconditioning (P/C):
HTC Vapor Phase
P-16744

<u>Electrical</u>	<u>Cum %</u>
233/0	0.0%

Infant / High Voltage Life
125°C, 7.0 V.
P-16774, P-16894

<u>48 Hr</u>	<u>336 Hr</u>	<u>1KHr</u>	<u>*Failure Rate</u>
231/0	77/0	77/1	67 Fits
		F1	

*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle
-55°C to +125°C
P-16895

<u>300 ~</u>	<u>1K ~</u>	<u>Cum %</u>
39/0	39/0	0.0%

Biased Moisture
85°C/85% RH, 5.5 V.
P-16896

<u>274 Hr</u>	<u>959 Hr</u>	<u>Cum %</u>
77/0	77/1	1.3%
	F2	

Storage Life
150°C, No bias
P-16897

<u>336 Hr</u>	<u>1KHr</u>	<u>Cum %</u>
38/0	38/0	0.0%

Failure Mode

F1: Read Matrix
F2: DQ Resistance